



Overview of the CEPC Vertex Detector

Zhijun Liang, Ying Zhang
(On behalf of the CEPC vertex detector group)



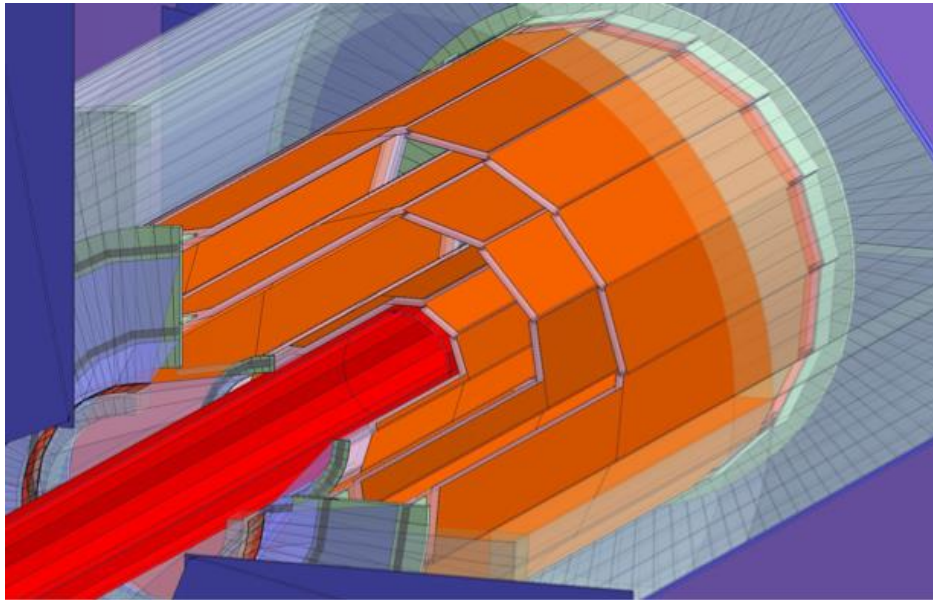
中國科學院高能物理研究所
Institute of High Energy Physics
Chinese Academy of Sciences

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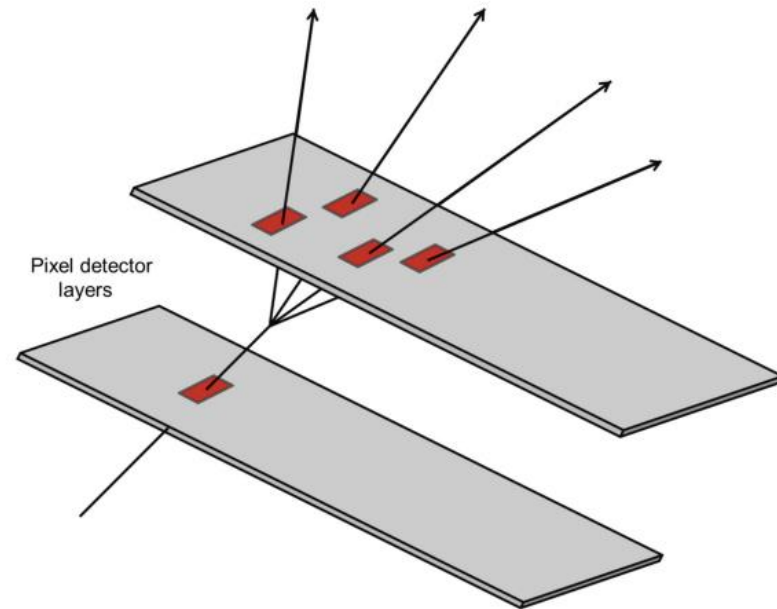
- Introduction
- Requirements
- Technology for CEPC reference TDR
- R&D efforts and results
- Detailed design including electronics, cooling and mechanics
- Readout electronics
- Performance from simulation
- Research team and working plan
- Summary

Introduction: vertex detector

- Vertex detector optimized for first 10 years of operation (ZH, low lumi-Z)
- Motivation:
 - Key detector for $H \rightarrow cc$ and $H \rightarrow gg$ physics, which is an important goal for CEPC
 - Aim to optimize impact parameter resolution and vertexing capability



CEPC vertex conceptual design (2016)



Vertex Requirement

- Inner most layer (b-layer) need to be positioned as close to beam pipe as possible

- Challenges: Radius (11.1 mm) is smaller compared with ALICE ITS3 (18 mm)

High background hit rate up to 39 MHz/cm² for low-luminosity Z mode

Table 4.2: Vertex Detector Design Parameters

Parameter	Design
Spatial Resolution	<u>$\sim 5 \mu\text{m}$</u>
Detector material budget	<u>$\sim 0.8\% X_0$</u>
First layer radius	11.1 mm
Power Consumption	<u>$< 40 \text{ mW/cm}^2$</u> (air cooling requirement)
Time stamp precision	100 ns
Fluence	$\sim 2 \times 10^{14} \text{ Neq/cm}^2$ (for first 10 years)
Operation Temperature	$\sim 5^\circ\text{C}$ to 30°C
Readout Electronics	Fast, low-noise, low-power
Mechanical Support	Ultralight structures
Angular Coverage	$ \cos \theta < 0.99$

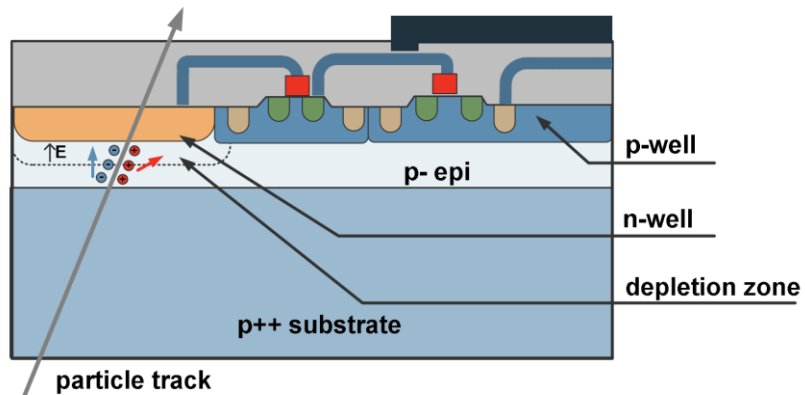
Technology for CEPC Reference TDR

■ Vertex detector technology selection

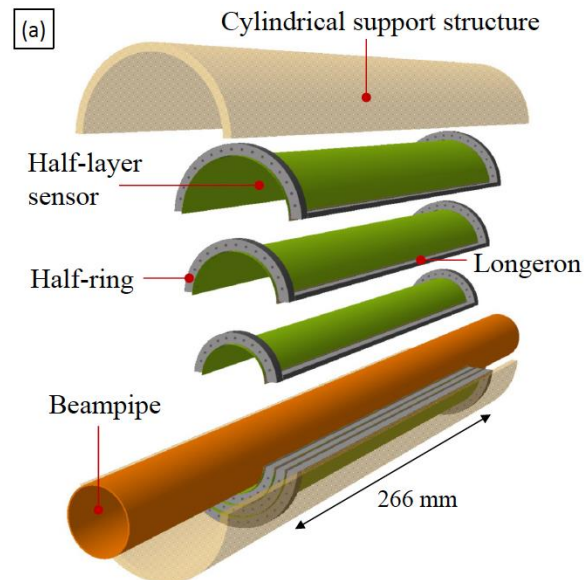
- Baseline: based on curved CMOS MAPS (Inspired by ALICE ITS3 design [1])
 - Advantage: 2~3 times smaller material budget compared to alternative (ladder)
- Alternative: Ladder design based on CMOS MAPS

Monolithic active Pixel Sensor (MAPS)

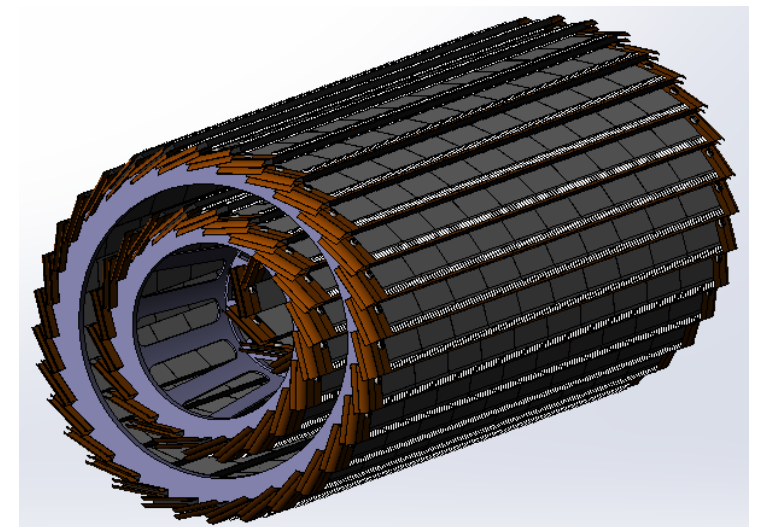
Monolithic Pixels



Baseline: curved MAPS



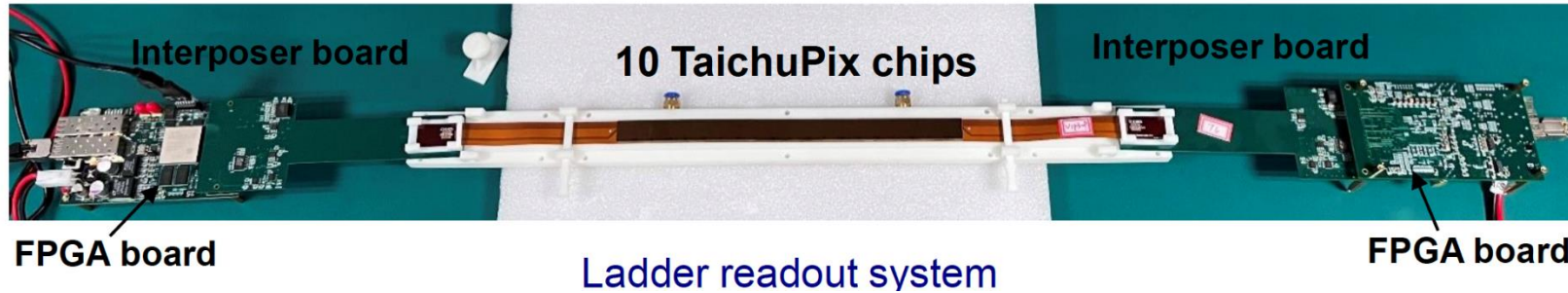
Alternative: ladder based MAPS



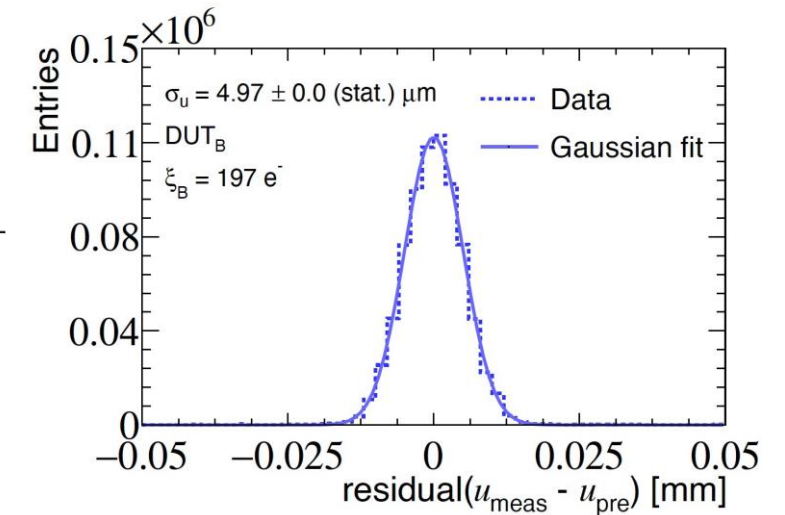
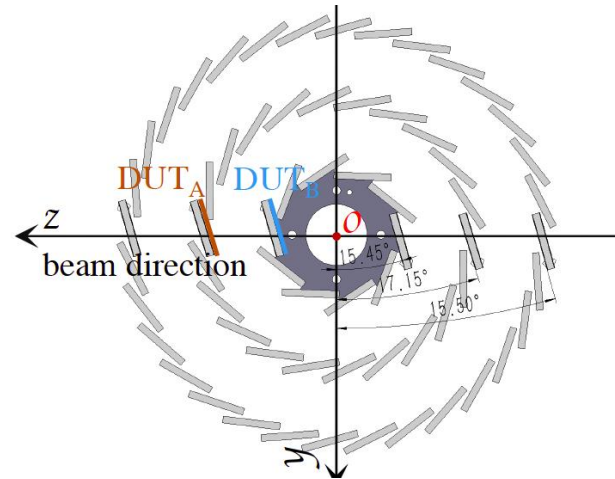
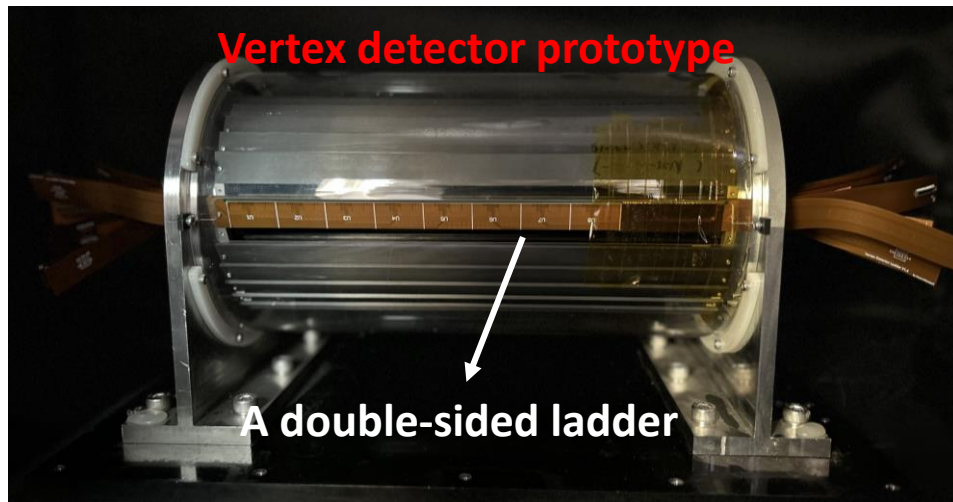
R&D status and final goal

Key technology	Status	CEPC Final goal
CMOS chip technology	Full-size chip with 180 nm CIS (TaichuPix-3)	65/55 nm CIS
Detector integration	Detector prototype with ladder design	Detector with bent silicon sensor
Spatial resolution	4.9 μm	3-5 μm
Detector cooling	Air cooling with 1% channels (24 chips) on	Air cooling with full power
Bent CMOS silicon	Bent Dummy wafer radius ~ 12 mm	Bent final wafer with radius ~ 11 mm
Stitching	11×11 cm ² stitched chip with 350 nm CIS	65/55 nm CIS stitched sensor

R&D effort: vertex detector prototype



TaichuPix-based prototype detector tested at DESY in April 2023
Spatial resolution $\sim 4.9 \mu\text{m}$
@ Detection efficiency $> 99\%$



	Status	CEPC Final goal
Detector integration	Detector prototype with ladder design	Detector with bent silicon design

R&D efforts curved MAPS

- CEPC b-layer radius (11 mm) smaller compared with ALICE ITS3 (radius = 18 mm)
- Feasibility : Mechanical prototype with dummy wafer can curved to a radius of 12 mm
 - The dummy wafer has been thinned to 40 μm

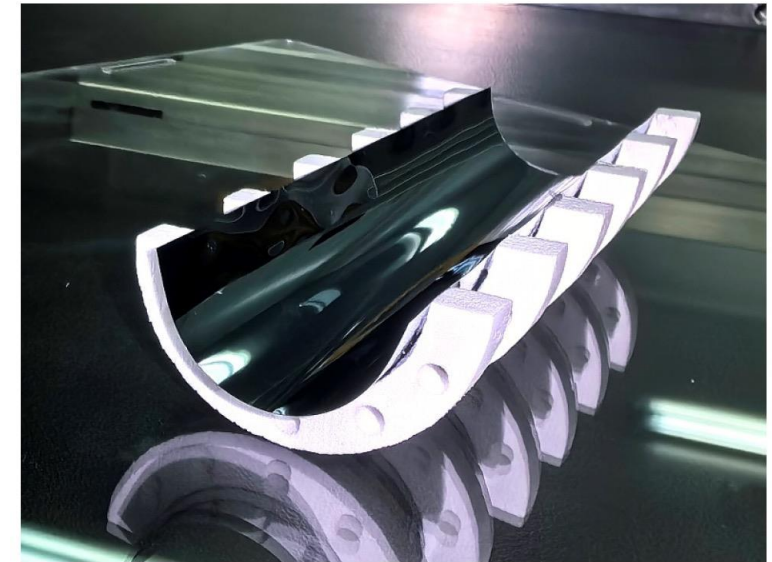
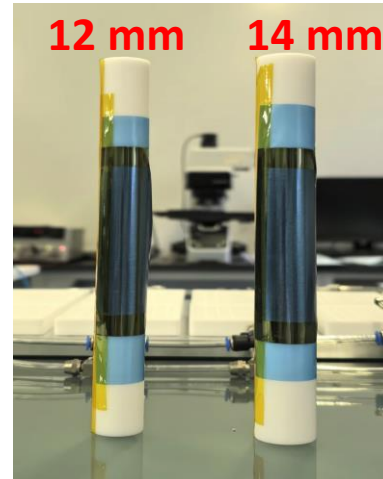
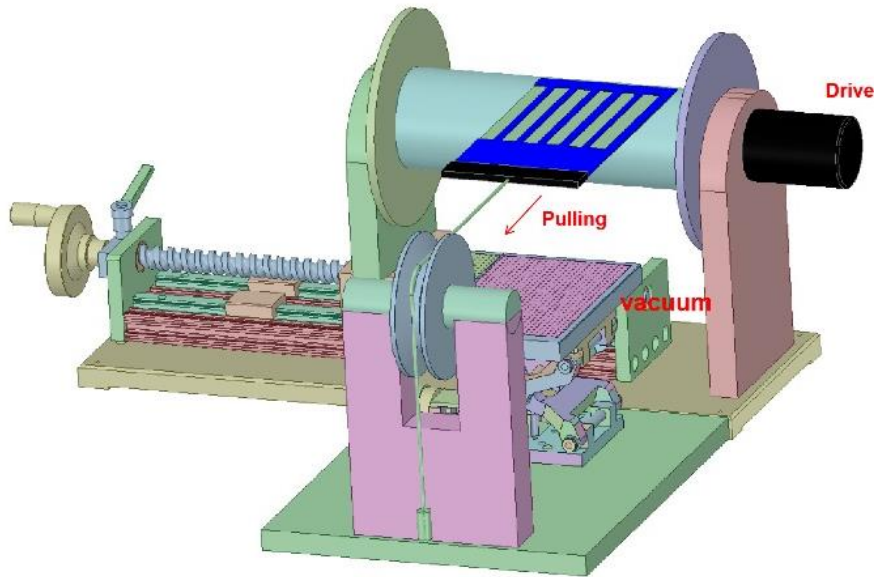
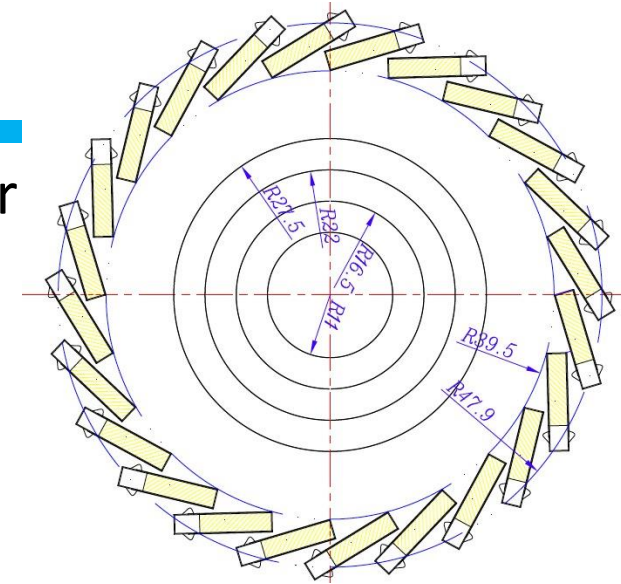


Figure 4.26: 12 mm bending radius.

	Status	CEPC Final goal
Bent silicon with radius	Bent Dummy wafer radius ~12 mm	Bent final wafer with radius ~11 mm

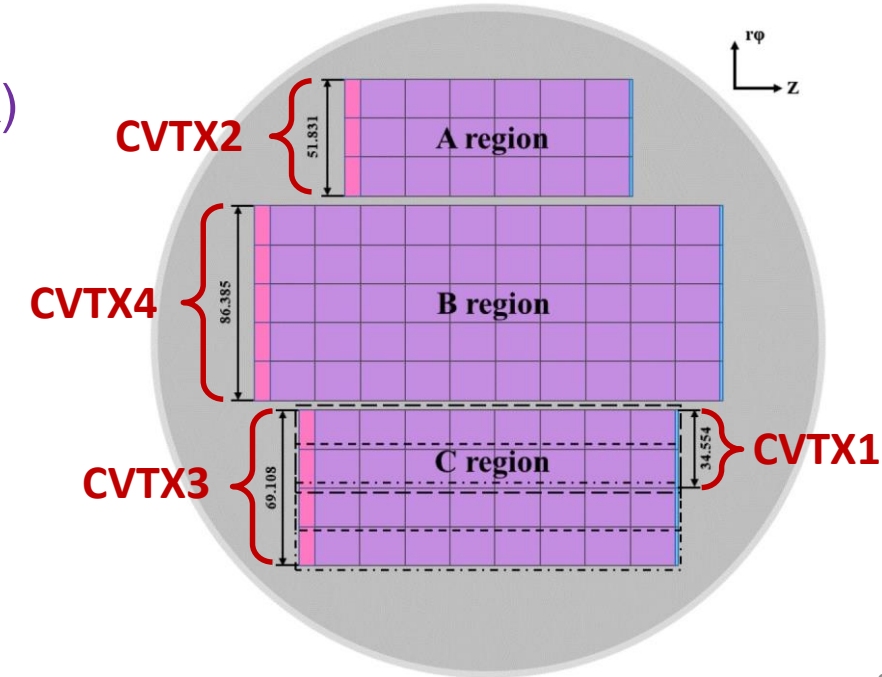
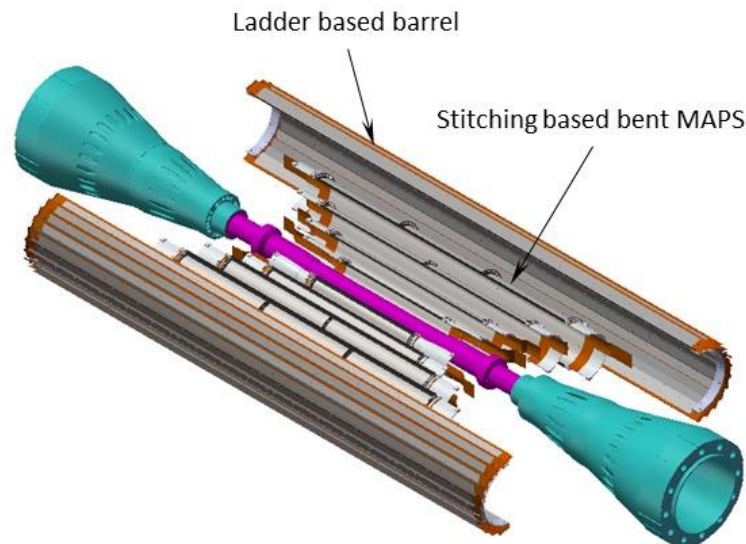
Baseline layout

- Baseline: 4 single layer of bent MAPS + 1 double-sided ladder layer
 - Alternative option: 3 double layer ladders
- Inner layer: using single bent MAPS ($\sim 0.15 \text{ m}^2$)
 - Low material budget $0.06\% X_0$ per layer
 - Different rotation angle in each layer to reduce dead area
- Outer layer: using double layer ladder ($\sim 0.3\% X_0/\text{layer}$)



Long barrel layout (no endcap disk)

CVTX/ PVTX X	radius mm	length mm
CVTX 1	11.1	161.4
CVTX 2	16.6	242.2
CVTX 3	22.1	323.0
CVTX 4	27.6	403.8
PVTX 5	39.5	682.0
PVTX 6	47.9	682.0



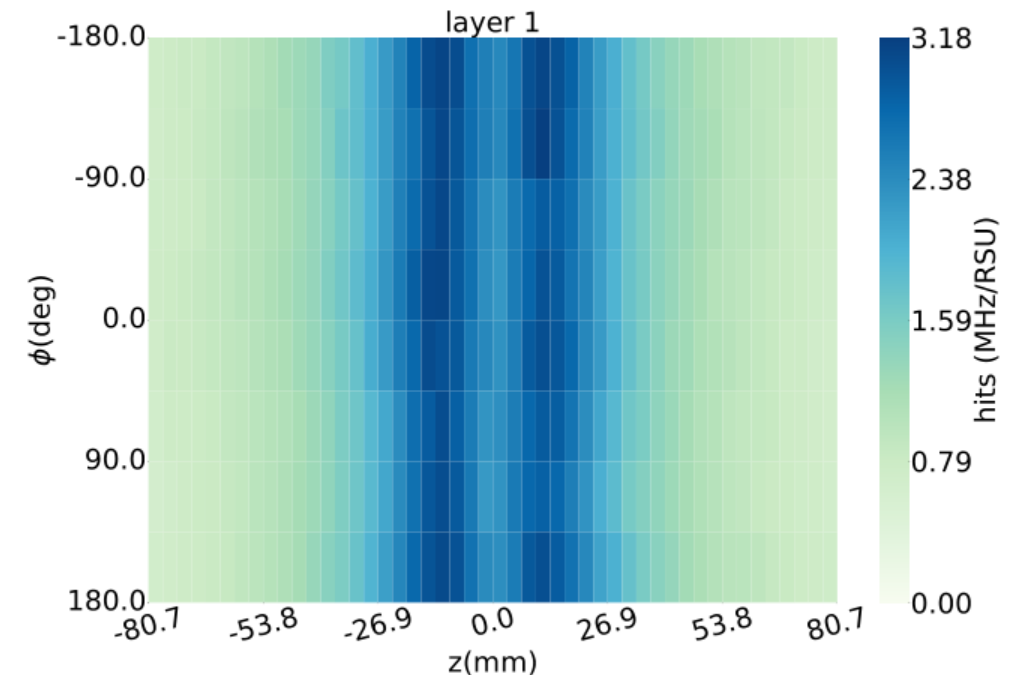
Background estimation

- The various sources of beam-induced backgrounds are simulated
 - The data rate at low-lumi Z pole is about ~Gbps level in b-layer

Background rate for Higgs and low-lumi Z runs

Layer	Ave. Hit Rate (MHz/cm ²)	Max. Hit Rate (MHz/cm ²)	Ave. Data Rate (Mbps/cm ²)	Max. Data Rate (Mbps/cm ²)
Higgs mode: Bunch Spacing: 277 ns, 63% Gap				
1	6.2	12	760	1500
2	0.84	1.6	87	160
3	0.17	0.36	19	38
4	0.067	0.16	8.4	19
5	0.017	0.037	2.1	4.2
6	0.013	0.026	1.6	3.7
Low-luminosity Z mode: Bunch Spacing: 69 ns, 17% Gap				
1	15	39	2700	8100
2	1.7	2.6	240	400
3	0.72	1.2	110	240
4	0.43	0.94	70	210
5	0.10	0.19	14	31
6	0.078	0.15	11	23

Hit rate map for 1st layer @ Higgs mode



Electronics

- Inner layers (L1-L4): stitching and RDL metal layers on wafer to transfer signal and power
 - Flexible Printed Circuit (FPC) connecting stitched sensors and Front-end Electronics Board (FEE)
 - FEE is installed in the service area outside of fast-LumiCal
- Outer layers (L5-L6): ladder on FPCs (also used in alternative design)
 - Signal, clock, control, power, ground will be handled by control board through FPCs

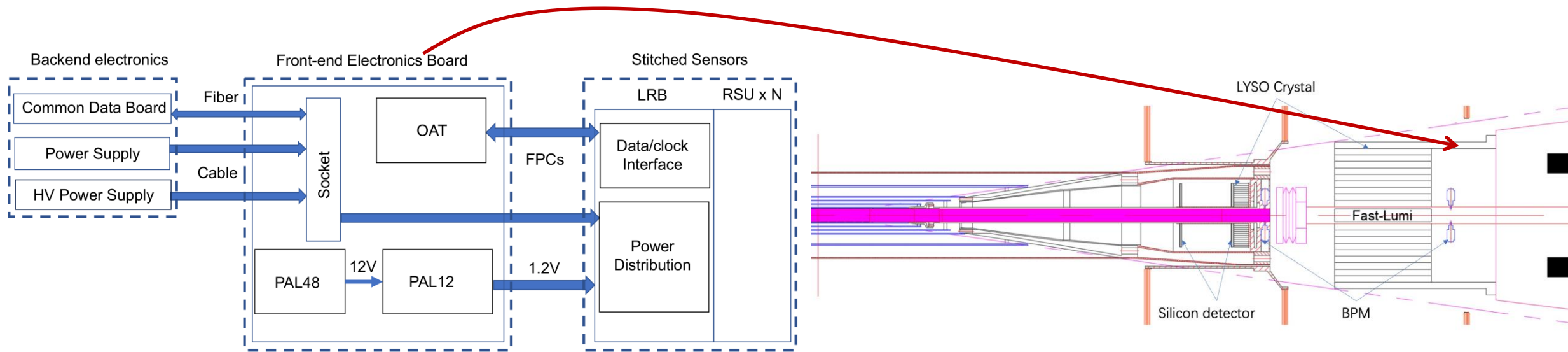
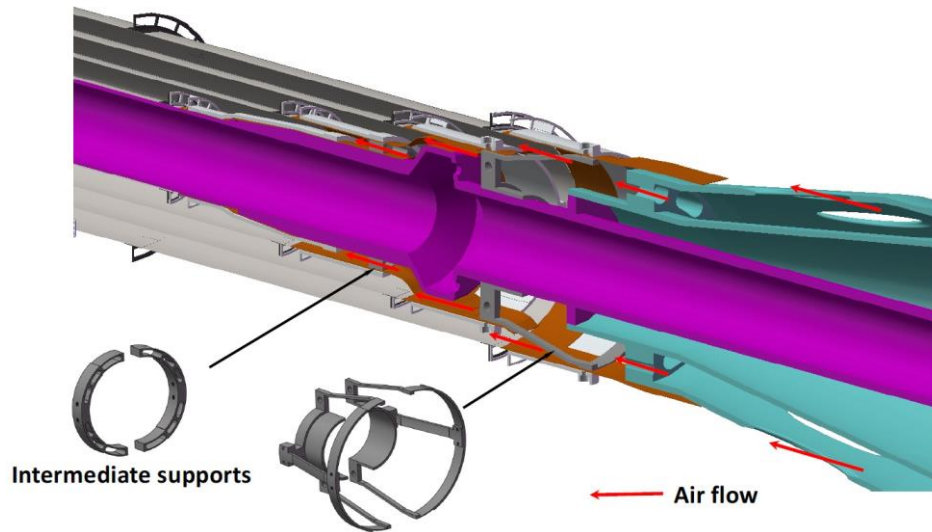


Diagram of the VTX readout electronics

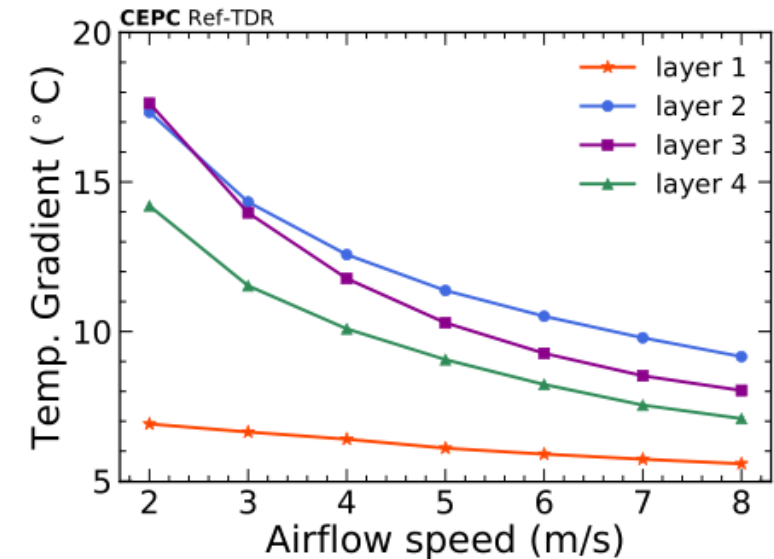
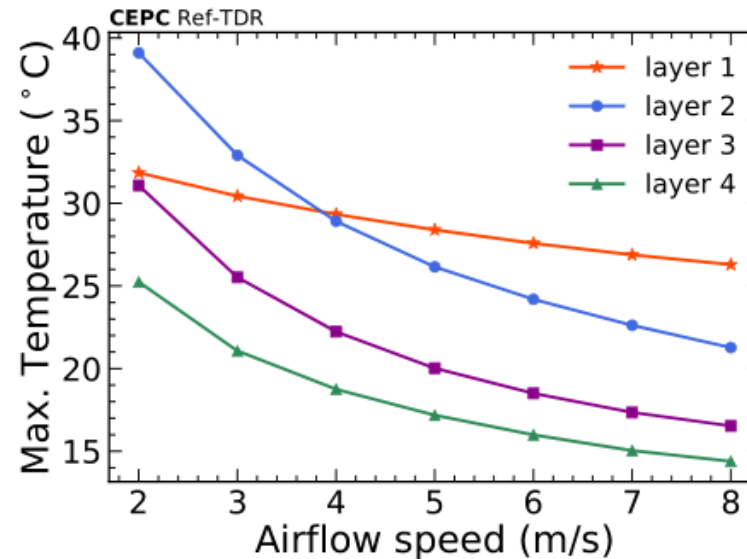
Location of the VTX service area

Mechanics and cooling

- For the sensitive area of stitched sensor, power consumption estimated to $\sim 40 \text{ mW/cm}^2$
- Air cooling feasibility study
 - Effective airflow cross section of 12.6 cm^2
 - Baseline layout can be cooled down below 30°C with 7 m/s air speed for stitching layers



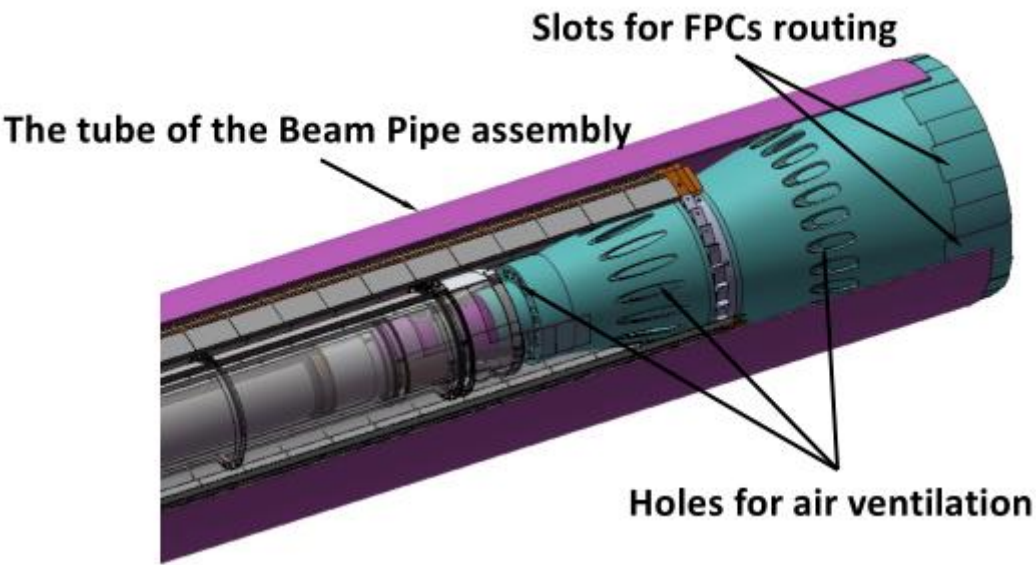
Installation of the half layers and intermediate support



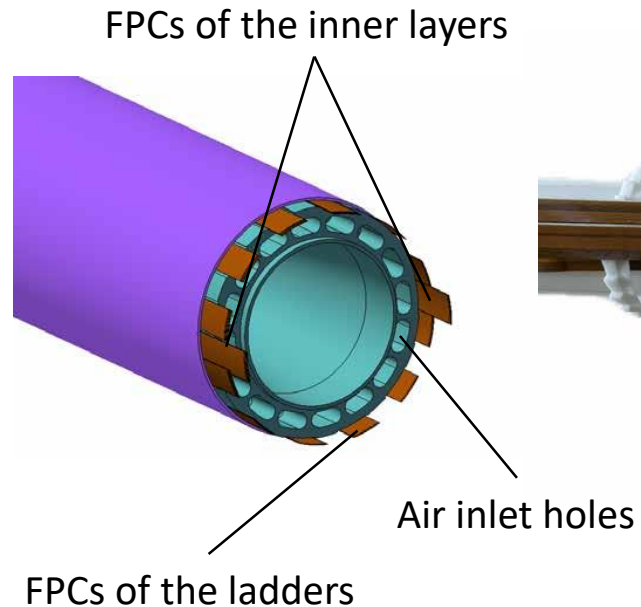
Thermal simulation results for the curved layers

Vertex technologies: cables and services

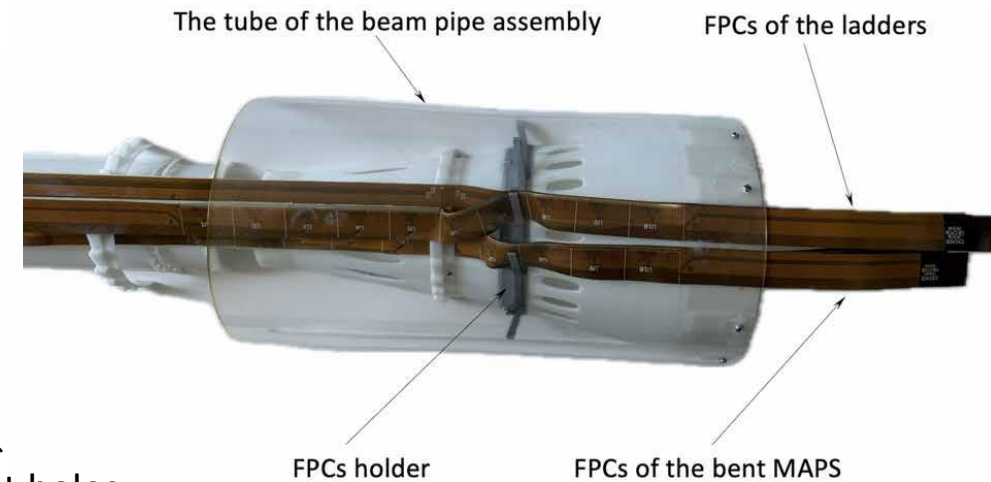
- A hollow conical structure integrated into the beam pipe assembly to serve as air distributor.
- A half-dummy 3D printed mechanical mockup was constructed
 - Validated there is enough space for cable routing and air cooling channel
 - The effective area for air cooling is 12.6 cm^2 (stitching layers) + 28 cm^2 (between L4/L5)



Cross-sectional view of the full assembly



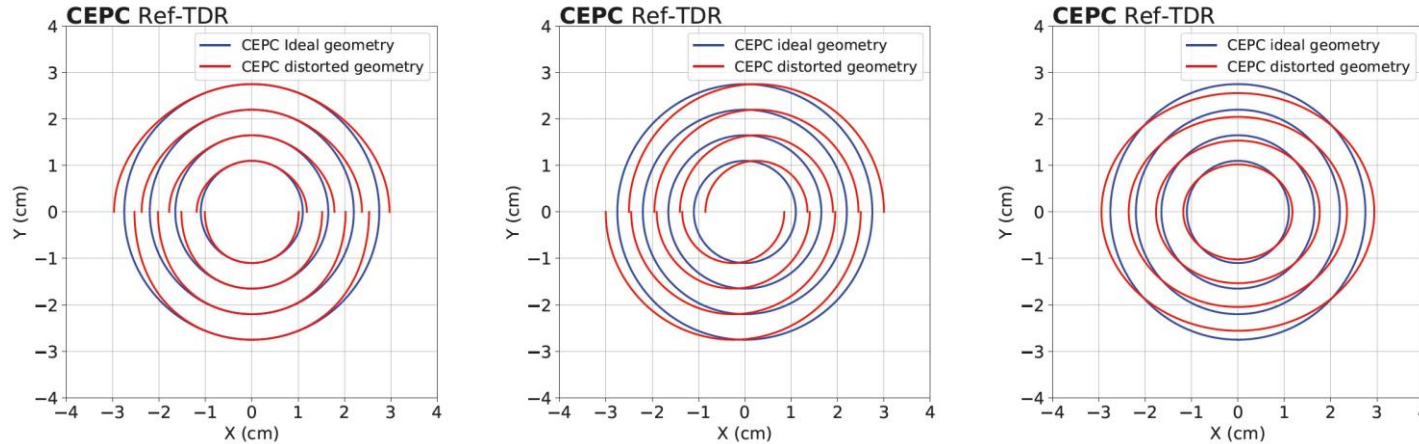
Dummy mockup of the VTX structure



Alignment in stitching layer

■ Deformation modes simulated by FEA

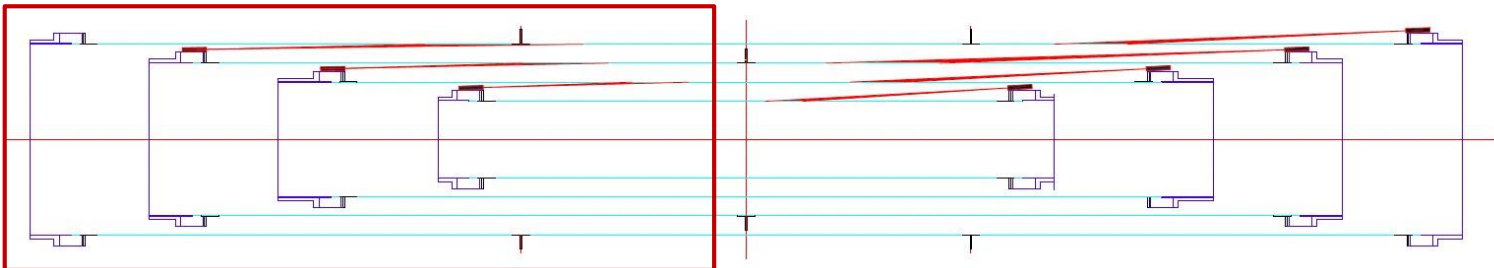
Hit positions with three deformed geometries



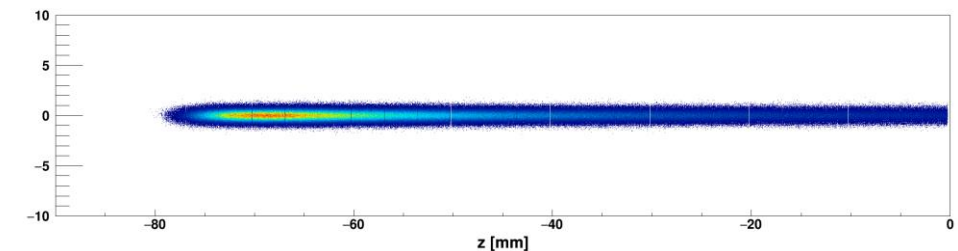
■ Real time deformation monitoring by a infrared laser alignment system

- laser sources are placed at both sides of the inner three layers and right side of the Layer 4

Back-side illuminations

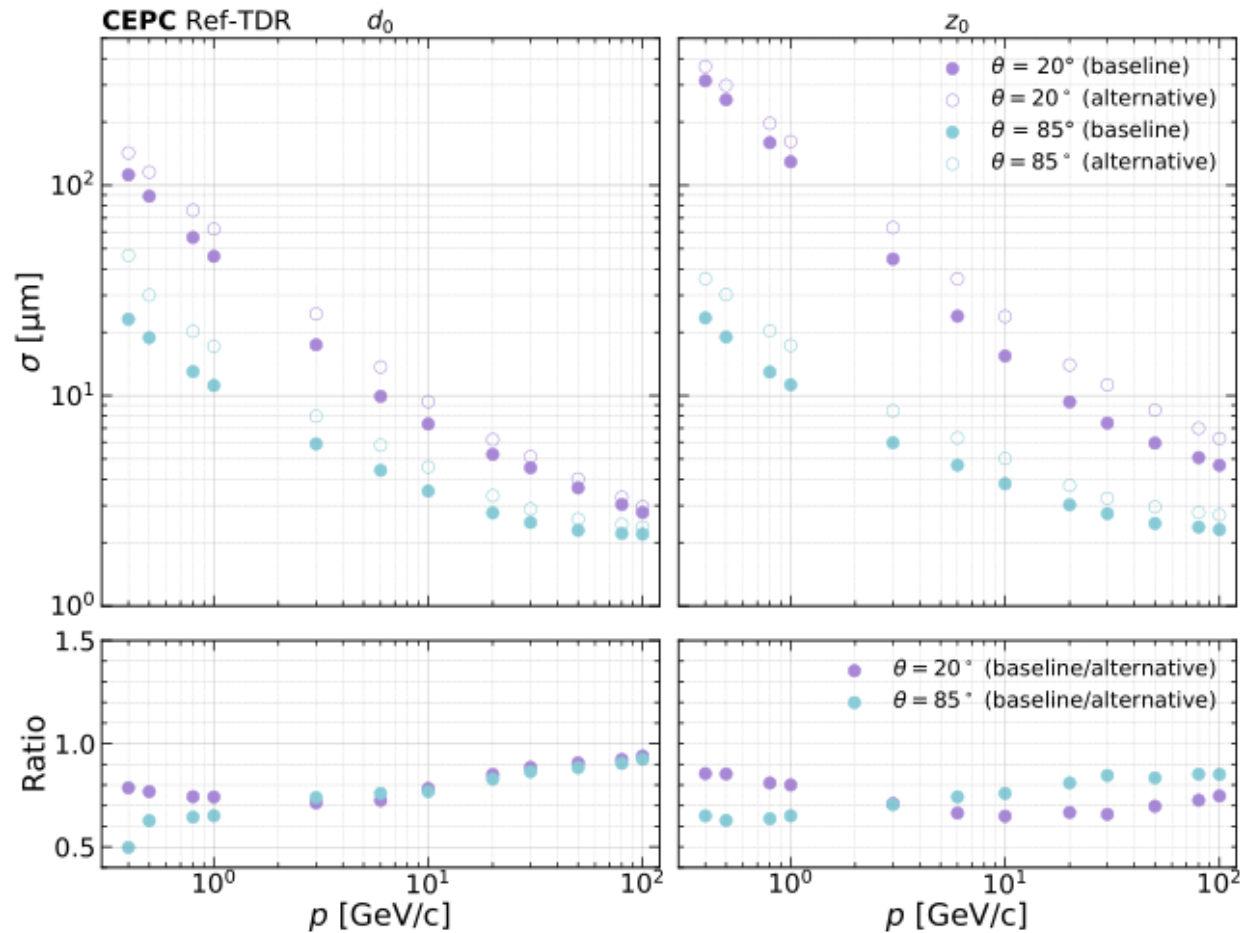


Laser beam spot on the Layer2 from (13 mm, 0, -85 mm)

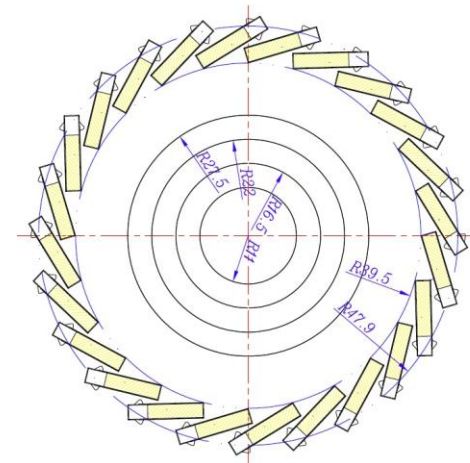


Performance: impact parameter resolution

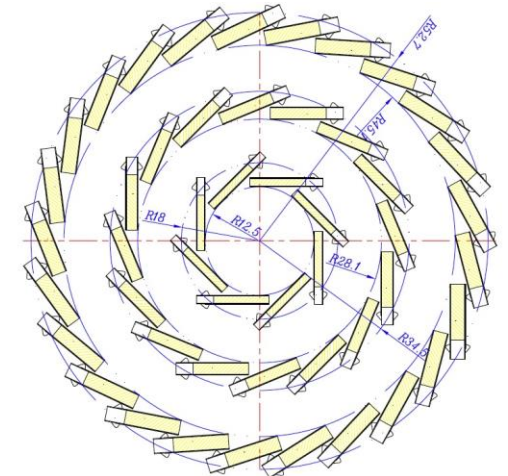
- Baseline has better resolution than alternative (ladder) (10-40%) in 0.4 GeV to 100 GeV



Baseline scheme
4 stitched curved sensor +
1 double layer ladders



Alternative scheme
3 double layer ladders

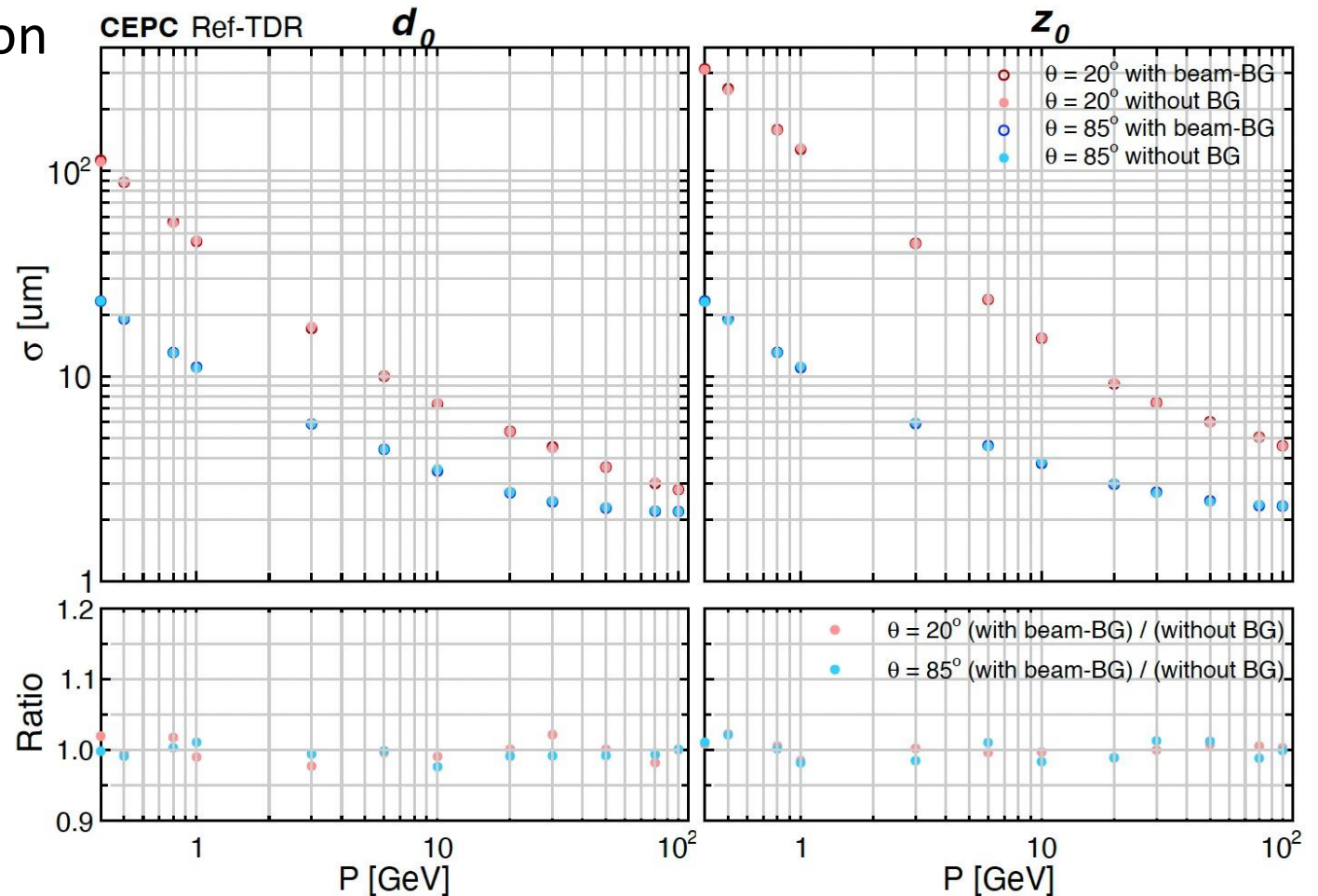


Impact parameter resolutions of d_0 and z_0 for the baseline and alternative

Performance with beam background

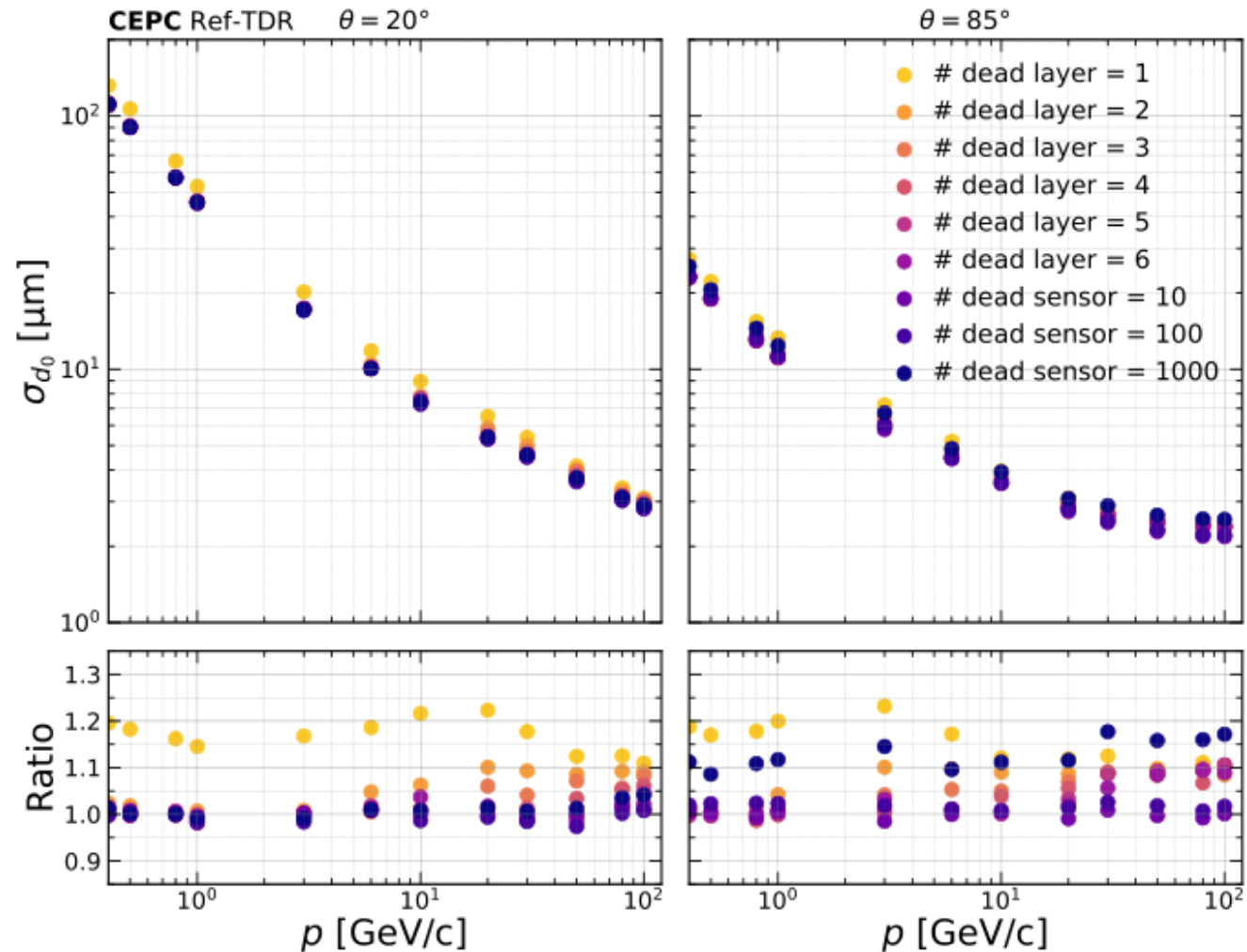
- The impact of beam background to performance has been studied.

- No visible effect in d_0/Z_0 resolution
- SR photons not accounted yet
 - Expected to be negligible



Performance: Efficiency

- Simulations assuming the complete loss of signal from one layer at a time.
- Any single layer loss leads to performance drop $\leq 25\%$, with the innermost layer contributing the most.
- VTX expected to maintain stable performance.



Research team

- IHEP: 8 faculty, 2 postdoc, 5 students
- IPHC/CNRS: 3 faculty, collaboration in framework of FCPPL and DRD3
 - CEPC Jadedpix design, ALICE/BELLE2 upgrade (especially on MAPS design, stitching)
- IFAE: Chip design , Sebastian Grinstein et al (2 faculty)
 - CEPC TaichuPix chip design, ATLAS upgrade
- ShanDong U.: Stitching chip design (3 faculty, 1 postdoc, 3 students)
- CCNU: Chip design, ladder assembly (2 faculty, 3 students)
- Northwestern Polytechnical U. : Chip design (5 faculty, 2 students)
- Nanchang U. : Chip design, (1 faculty, 1 student)
- Nanjing U.: Irradiation study, chip design : (2 faculty, 4 students)
- NanKai U.: Physics performance (1 faculty, 1 student)
- CERN: Recent joint R&D collaboration aiming for ALICE3 upgrade

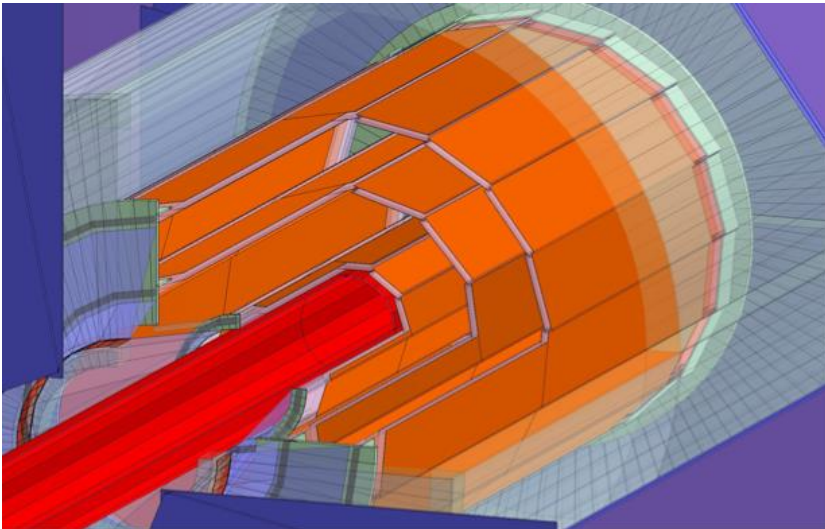
Working plan

- Development of wafer-scale stitched MAPSs.
 - Develop wafer-scale stitching with 180 nm technology
 - The second-generation stitched chip will transition to 65 nm/55 nm
 - Baseline: TPSCo's 65 nm technology
 - Alternative: HLMC's 55 nm technology
- Ultra-thin mechanical supports and low-mass integration techniques.
 - Start with prototype with dummy silicon wafer
- Construction of a full-scale VTX prototype to address challenges in mechanical precision, cooling performance, laser alignment, and system-level integration.

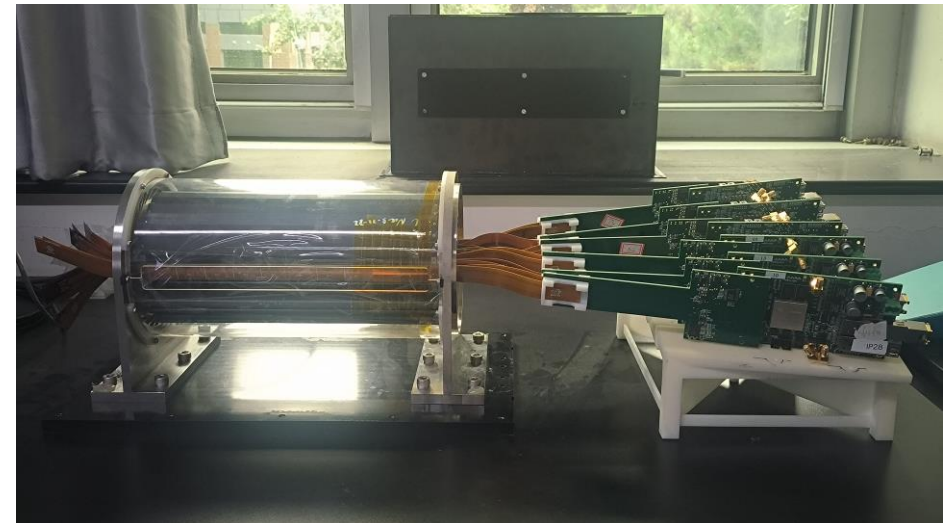
Summary

- Completed reference TDR for CECP vertex detector
 - Aiming for stitching technology as baseline design for reference TDR
- We active expanding international collaboration and explore synergies with other projects
 - Recent collaboration with CERN on ALICE3 tracker upgrade
 - We are members of ECFA DRD3 collaboration

CEPC vertex conceptual design (2016)

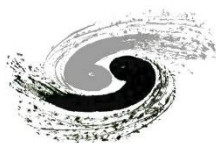


CEPC vertex prototype (2023)





Thank you for your attention!



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